



ON Semiconductor®

October 2018

# FTCO3V85A1

## 3-Phase Automotive Power Module for DC-DC Converter

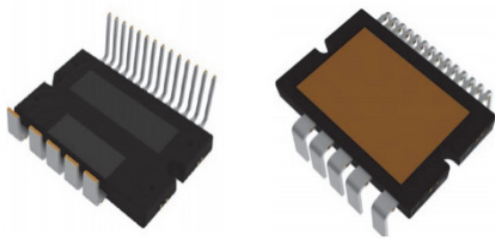
### General Description

The FTCO3V85A1 is an 80V low Rds(on) automotive qualified power module, featuring a 3-phase MOSFET bridge optimized for Automotive 48V-12V interleaved DC-DC converter system, It includes a precision shunt resistor for current sensing, an NTC for temperature sensing, and an RC snubber circuit.

The module utilizes ON's trench MOSFET technology and it is designed to provide a very compact and high efficiency solution for DC-DC converter system. The Power module is 100% lead free, RoHs and UL compliant.

### Benefits

- Low junction-sink thermal resistance
- Low power loss for high efficiency in DC-DC system design
- Low electrical resistance
- Compact DC-DC converter design
- Highly integrated compact design
- Better EMI and electrical isolation
- Easy and reliable installation
- High current handling
- Improved overall system reliability



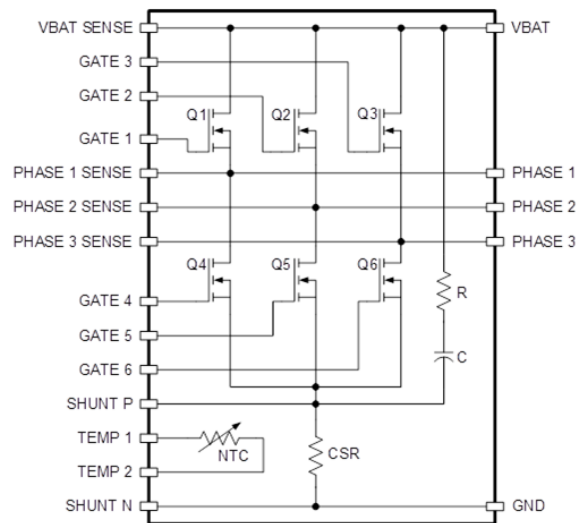
Package

### Features

- 3-Phase 1.5kW 48V-12V interleaved DC-DC converter
- 80V-125A trench MOSFETs for high-side  
80V-160A trench MOSFETs for low-side
- Precise shunt current sensing
- Temperature sensing
- DBC substrate
- 100% lead free and RoHS compliant 2000/53/C directive.
- UL94V-0 compliant
- Isolation rating of 2500Vrms/min
- Mounting through screws
- Automotive qualified

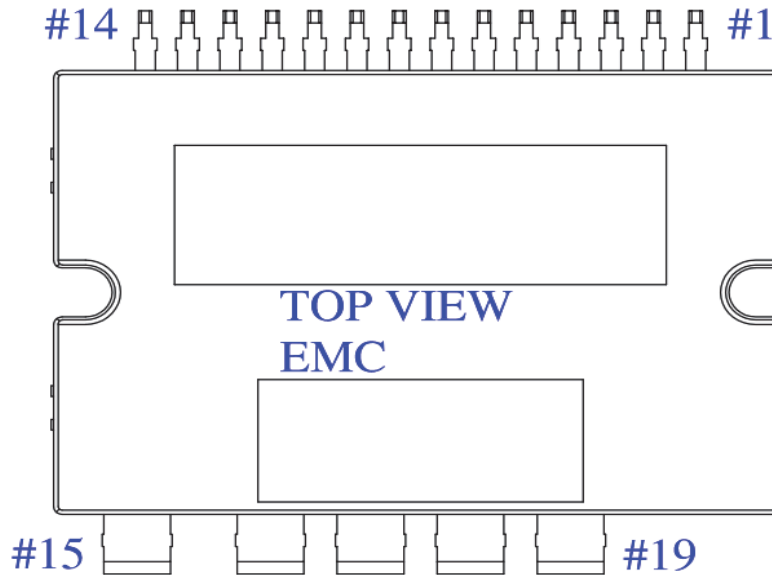
### Applications

- DC-DC converter



Schematic

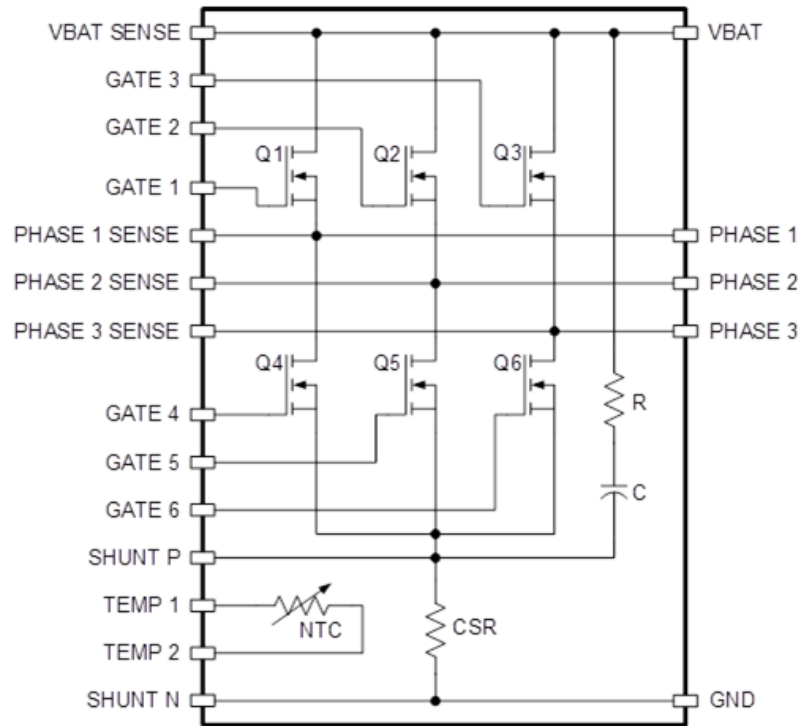
## Pin Configuration



## Pin Description

Pin Number	Pin Number	Pin Descriptions
1	TEMP 1	NTC Thermistor Terminal 1
2	TEMP 2	NTC Thermistor Terminal 2
3	PHASE 3 SENSE	Source of Q3 and Drain of Q6
4	GATE 3	Gate of Q3, high side Phase 3 MOSFET
5	GATE 6	Gate of Q6, low side Phase 3 MOSFET
6	PHASE 2 SENSE	Source of Q2 and Drain of Q5
7	GATE 2	Gate of Q2, high side Phase 2 MOSFET
8	GATE 5	Gate of Q5, low side Phase 2 MOSFET
9	PHASE 1 SENSE	Source of Q1 and Drain of Q4
10	GATE 1	Gate of Q1, high side Phase 1 MOSFET
11	VBAT SENSE	Sense pin for battery voltage and Drain of high side MOSFETs
12	GATE 4	Gate of Q4, low side Phase 1 MOSFET
13	SHUNT P	Positive CSR sense pin and source connection for low side MOSFETs
14	SHUNT N	Negative CSR sense pin and sense pin for battery return
15	VBAT	Battery voltage power lead
16	GND	Battery return power lead
17	PHASE 1	Phase 1 power lead
18	PHASE 2	Phase 2 power lead
19	PHASE 3	Phase 3 power lead

Internal Equivalent Circuit



**Flammability Information**

All materials present in the power module meet UL flammability rating class 94V-0 or higher.

**Solder**

Solder used is a lead free SnAgCu alloy.

**Compliance to RoHS**

The Power Module is 100% lead free and RoHS compliant with the 2000/53/C directive.

**Absolute Maximum Ratings** ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Specified)

Symbol	Parameter	Rating	Unit
$V_{DS}(Q1\sim Q6)$	Drain to Source Voltage	80	V
$V_{GS}(Q1\sim Q6)$	Gate to Source Voltage	$\pm 20$	V
$I_D$ (high-side)	Drain Current Continuous ( $TC = 25^\circ\text{C}$ , $T_J = 175^\circ\text{C}$ , $V_{GS} = 10\text{V}$ ) (*Note 1)	125	A
$I_D$ (low-side)	Drain Current Continuous ( $TC = 25^\circ\text{C}$ , $T_J = 175^\circ\text{C}$ , $V_{GS} = 10\text{V}$ ) (*Note 1)	160	A
$E_{AS}(Q1\sim Q3)$	Single Pulse Avalanche Energy (*Note 2)	190	mJ
$E_{AS}(Q4\sim Q6)$	Single Pulse Avalanche Energy (*Note 2)	324	mJ
$P_D$ (high-side)	Power dissipation ( $TC = 25^\circ\text{C}$ , $T_J = 175^\circ\text{C}$ )	115	W
$P_D$ (low-side)	Power dissipation ( $TC = 25^\circ\text{C}$ , $T_J = 175^\circ\text{C}$ )	135	W
$T_J$	Maximum Junction Temperature	175	$^\circ\text{C}$
$T_{STG}$	Storage Temperature	125	$^\circ\text{C}$

**Thermal Resistance**

Symbol	Parameter	Min.	Typ.	Max.	Unit
R <sub>thjc</sub> Thermal Resistance Junction to case, Single FET, (*Note 3)	Q1 Thermal Resistance J -C	-	1.0	1.3	$^\circ\text{C}/\text{W}$
	Q2 Thermal Resistance J -C	-	1.0	1.3	$^\circ\text{C}/\text{W}$
	Q3 Thermal Resistance J -C	-	1.0	1.3	$^\circ\text{C}/\text{W}$
	Q4 Thermal Resistance J -C	-	0.8	1.1	$^\circ\text{C}/\text{W}$
	Q5 Thermal Resistance J -C	-	0.8	1.1	$^\circ\text{C}/\text{W}$
	Q6 Thermal Resistance J -C	-	0.8	1.1	$^\circ\text{C}/\text{W}$
$T_J$	Maximum Junction Temperature	-		175	$^\circ\text{C}$
$T_S$	Operating Sink Temperature	-40		120	$^\circ\text{C}$
$T_{STG}$	Storage Temperature	-40		125	$^\circ\text{C}$

**Notes:**

- \* Note 1 - Max value not to exceed  $T_J=175^\circ\text{C}$  based on max limitation of R<sub>thjc</sub> thermal limitation and R<sub>dson</sub>. Defined by design, not subject production testing.
- \* Note 2 - For Q1-Q3: Starting  $T_J = 25^\circ\text{C}$ ,  $L = 0.08\text{mH}$ ,  $I_{AS} = 69\text{A}$ ,  $V_{DD} = 80\text{V}$  during inductor charging and  $V_{DD} = 0\text{V}$  during time in avalanche. For Q4-Q6: Starting  $T_J = 25^\circ\text{C}$ ,  $L = 0.08\text{mH}$ ,  $I_{AS} = 90\text{A}$ ,  $V_{DD} = 80\text{V}$  during inductor charging and  $V_{DD} = 0\text{V}$  during time in avalanche.
- \* Note 3 - Test method compliant with MIL STD 883-1012.1.

**Electrical Characteristics** ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$BV_{DSS}$	D-S Breakdown Voltage (Inverter MOSFETs)	$V_{GS} = 0V, I_D = 250\mu A$	80	-	-	V
$V_{GS}$	Gate to Source Voltage (Inverter MOSFETs)	Gate-to-Source Voltage	-20	-	20	V
$V_{TH}$	Threshold Voltage (Q1-Q6)	$V_{GS} = V_{DS}, I_D = 250\mu A, T_J = 25^\circ\text{C}$	2	3	4	V
$V_{SD}$	MOSFET Body Diode Forward Voltage	$V_{GS} = 0V, I_S = 80A, T_J = 25^\circ\text{C}$	-	-	1	V
$R_{DS(ON)Q1}$	Inverter High Side MOSFETs Q1 (See *Note4)	$V_{GS} = 10V, I_D = 80A, T_J = 25^\circ\text{C}$	-	2.4	3.5	m $\Omega$
$R_{DS(ON)Q2}$	Inverter High Side MOSFETs Q2 (See *Note4)	$V_{GS} = 10V, I_D = 80A, T_J = 25^\circ\text{C}$	-	2.4	3.5	m $\Omega$
$R_{DS(ON)Q3}$	Inverter High Side MOSFETs Q3 (See *Note4)	$V_{GS} = 10V, I_D = 80A, T_J = 25^\circ\text{C}$	-	2.5	3.7	m $\Omega$
$R_{DS(ON)Q4}$	Inverter Low Side MOSFETs Q4 (See *Note4)	$V_{GS} = 10V, I_D = 80A, T_J = 25^\circ\text{C}$	-	1.9	2.6	m $\Omega$
$R_{DS(ON)Q5}$	Inverter Low Side MOSFETs Q5 (See *Note4)	$V_{GS} = 10V, I_D = 80A, T_J = 25^\circ\text{C}$	-	2.1	2.8	m $\Omega$
$R_{DS(ON)Q6}$	Inverter Low Side MOSFETs Q6 (See *Note4)	$V_{GS} = 10V, I_D = 80A, T_J = 25^\circ\text{C}$	-	2.4	3.1	m $\Omega$
$I_{GSS}$	Inverter MOSFETs (UH,UL,VH,VL,WH,WL)	$V_{GS} = \pm 20V, V_{DS} = 0V, T_J = 25^\circ\text{C}$	-	-	$\pm 100$	nA
$I_{DSS}$	Inverter MOSFETs Drain to Source Leakage Current	$V_{GS} = 0V, V_{DS} = 80V, T_J = 25^\circ\text{C}$	-	-	2	$\mu A$
Total loop resistance VLINK(+) - V0 (-)		$V_{GS} = 10V, I_D = 80A, T_J = 25^\circ\text{C}$	-	5.9	7.5	m $\Omega$

\* Note 4 - High side Q1,Q2,Q3 have same die size and Rdson, Low side Q4,Q5,Q6 have same die size and Rdson. For lowest power loss, High and Low side MOSFETs have different die size and Rdson. The different Rdson values listed in the datasheet are due to the different access points available inside the module for Rdson measurement. While the high side MOSFETs (Q1, Q2, Q3) have source sense wire bonds, the low side MOSFETs (Q4, Q5, Q6) do not have source sense wire bonds, thus resulting in higher Rdson values.

**Temperature Sense (NTC Thermistor)**

Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Voltage	Current=1mA, Temperature=25°C	7.5	-	12	V

**Current Sense Resistor**

Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Resistance	Current Senset resistor current = 80A (See *Note5)	0.47	-	0.51	m $\Omega$

\* Note 5 - Module level measurement.

	Components	Spec	Quantity	Size
1	MOSFET	PT7 80V,bare die Rdson 2.25m $\Omega$ typical	3ea (Q1-Q3)	195 mil x 95 mil
2	MOSFET	PT7 80V,bare die Rdson 1.35m $\Omega$ typical	3ea (Q4-Q6)	200 mil x 145 mil
3	Resistor	1ohm 0.5W	1ea	142 mil x 55 mil
4	Capacitor	0.022uF 100V	1ea	79 mil x 49 mil
5	CSR	1% tolerance, 0.5ohm	1ea	250 mil x 120 mil
6	NTC	1% tolerance, 10kohm	1ea	63 mil x 32 mil

## Dynamic Characteristic

$C_{iss}$	Input Capacitance	$V_{DS} = 40V, V_{GS} = 0V,$ $f = 1MHz$ for Q1-Q3 (High side MOSFET)	-	6320	-	pF	
$C_{oss}$	Output Capacitance		-	1030	-	pF	
$C_{rfs}$	Reverse Transfer Capacitance		-	32	-	pF	
$C_{iss}$	Input Capacitance	$V_{DS} = 40V, V_{GS} = 0V,$ $f = 1MHz$ for Q4-Q6 (Low side MOSFET)	-	10000	-	pF	
$C_{oss}$	Output Capacitance		-	1400	-	pF	
$C_{rfs}$	Reverse Transfer Capacitance		-	95	-	pF	
$R_G$	Gate Resistance	$V_{GS} = 0V, f = 1MHz$ for Q1-Q3 (High side MOSFET)	-	2.1	-	$\Omega$	
$R_G$	Gate Resistance	$V_{GS} = 0V, f = 1MHz$ for Q4-Q6 (Low side MOSFET)	-	3.3	-	$\Omega$	
$Q_{g(TOT)}$	Total Gate Charge at 10V	$V_{GS} = 0$ to 10V	$V_{DD} = 64V$ $I_D = 80A$ $I_g = 1mA$	-	86	112	nC
$Q_{g(TH)}$	Threshold Gate Charge	$V_{GS} = 0$ to 2V		-	12	18	nC
$Q_{gs}$	Gate to Source Gate Charge	for Q1-Q3		-	30	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	(High side MOSFET)		-	18	-	nC
$Q_{g(TOT)}$	Total Gate Charge at 10V	$V_{GS} = 0$ to 10V		-	131	150	nC
$Q_{g(TH)}$	Threshold Gate Charge	$V_{GS} = 0$ to 2V		-	18	21	nC
$Q_{gs}$	Gate to Source Gate Charge	for Q4-Q6		-	47	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	(Low side MOSFET)		-	24	-	nC

**Typical Characteristics** (The dynamic, switching characteristics and graphs are in reference to the FDBL86366\_F085 (TOLL) datasheet (High side MOSFET)

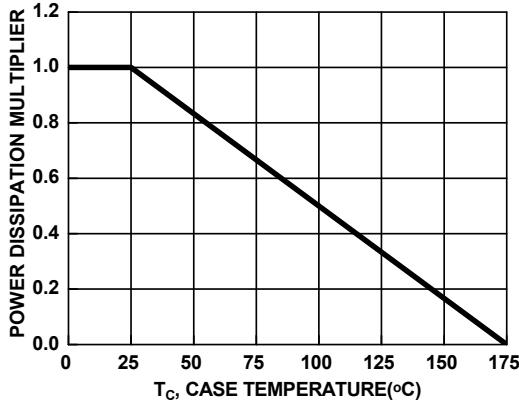


Figure 1. Normalized Power Dissipation vs. Case Temperature

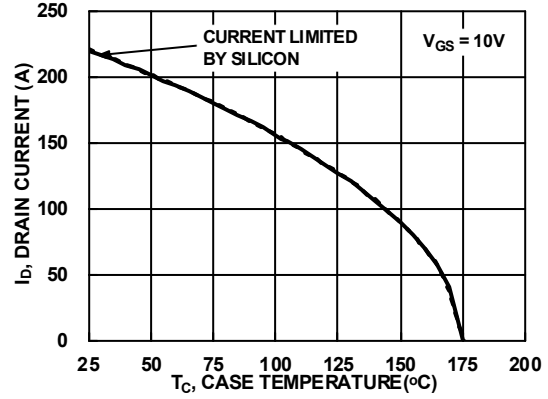


Figure 2. Maximum Continuous Drain Current vs. Case Temperature

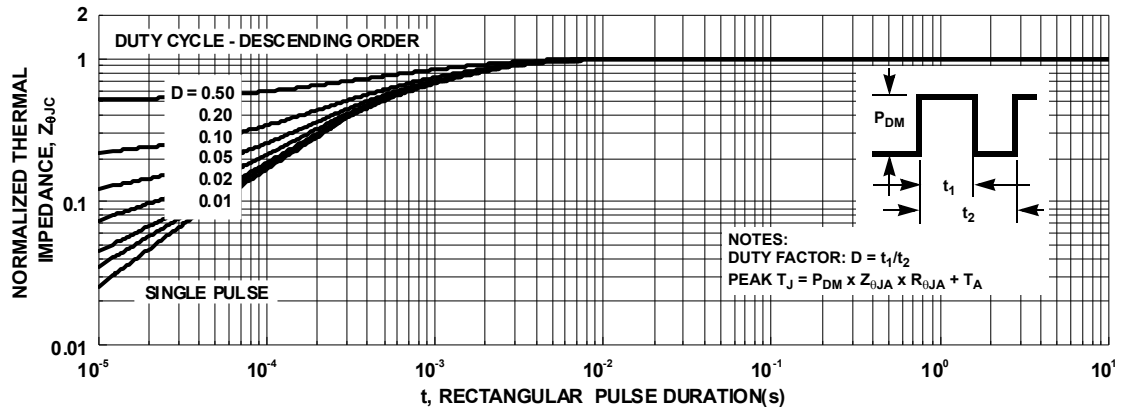


Figure 3. Normalized Maximum Transient Thermal Impedance

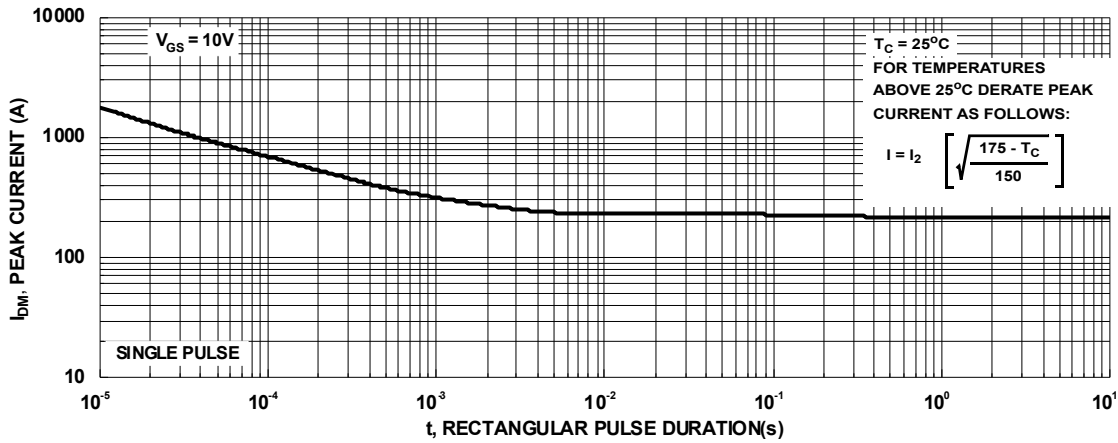


Figure 4. Peak Current Capability



## Typical Characteristics (The dynamic, switching characteristics and graphs are in reference to the FDBL86366\_F085

(TOLL) datasheet (High side MOSFET)

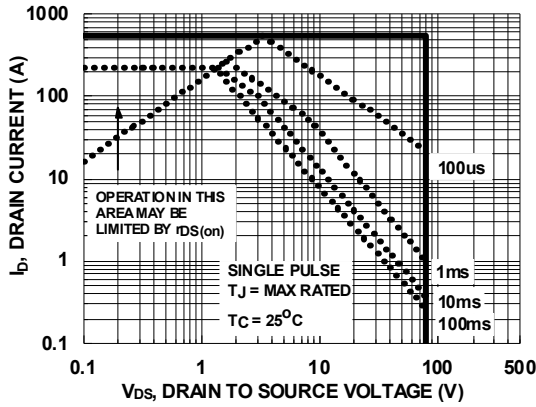


Figure 5. Forward Bias Safe Operating Area

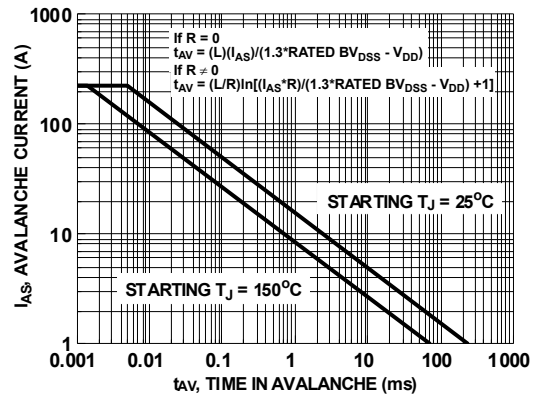


Figure 6. Unclamped Inductive Switching Capability

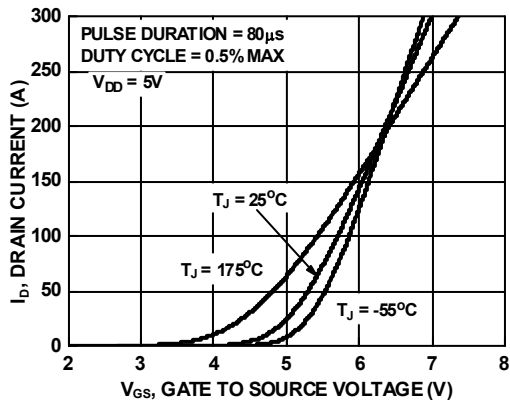


Figure 7. Transfer Characteristics

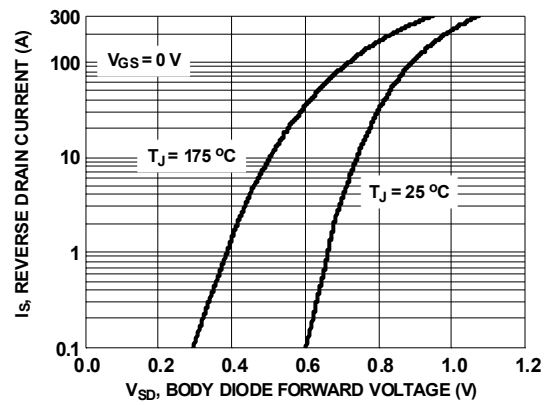


Figure 8. Forward Diode Characteristics

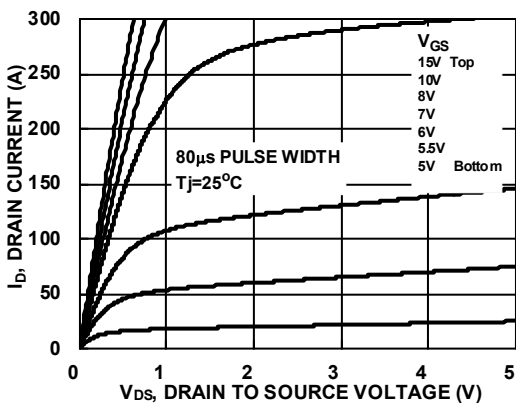


Figure 9. Saturation Characteristics

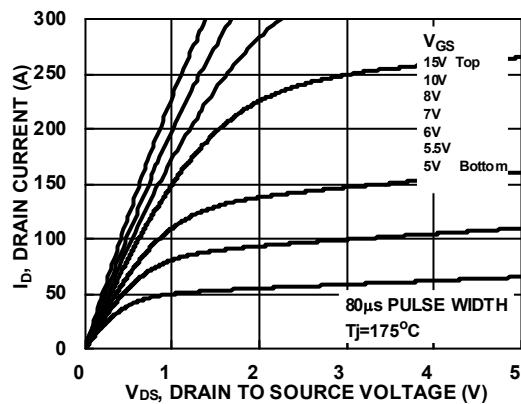


Figure 10. Saturation Characteristics

**Typical Characteristics** (The dynamic, switching characteristics and graphs are in reference to the FDBL86366\_F085

(TOLL) datasheet (High side MOSFET)

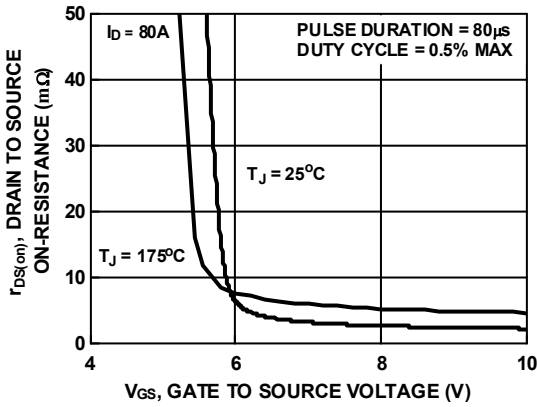


Figure 11.  $R_{DS(on)}$  vs. Gate Voltage

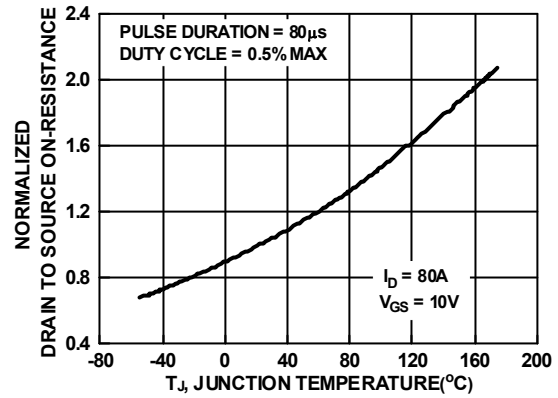


Figure 12. Normalized  $R_{DS(on)}$  vs. Junction Temperature

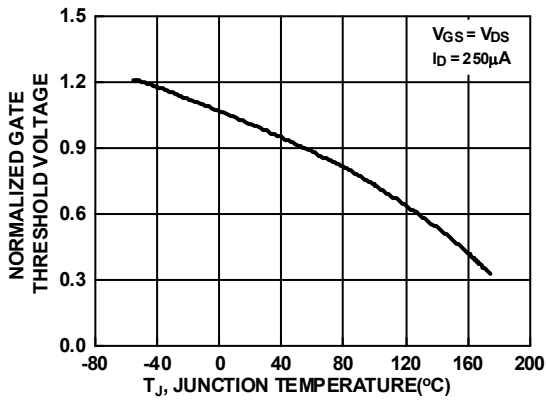


Figure 13. Normalized Gate Threshold Voltage vs. Temperature

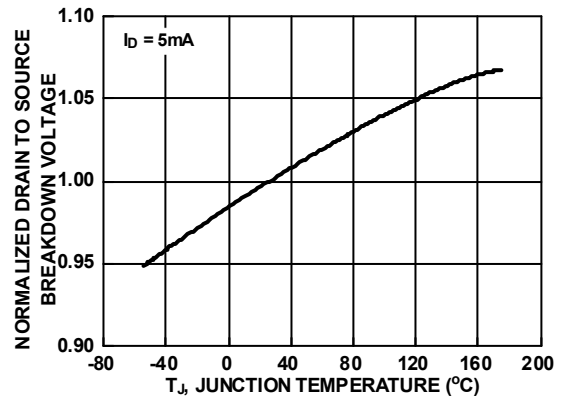


Figure 14. Normalized Drain to Source Breakdown Voltage vs. Junction Temperature

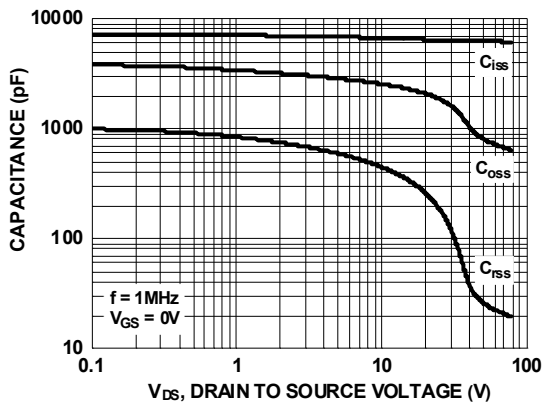


Figure 15. Capacitance vs. Drain to Source Voltage

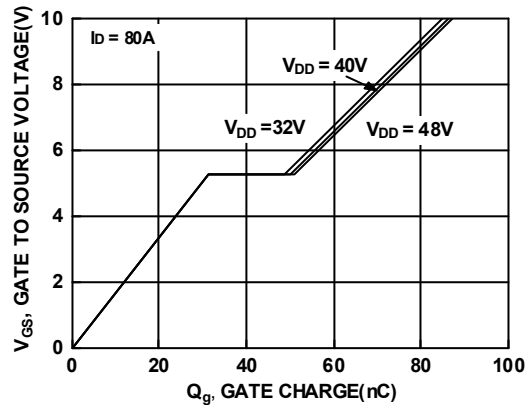


Figure 16. Gate Charge vs. Gate to Source Voltage

**Typical Characteristics** (The dynamic, switching characteristics and graphs are in reference to the FDBL86363\_F085 (TOLL) datasheet (Low side MOSFET))

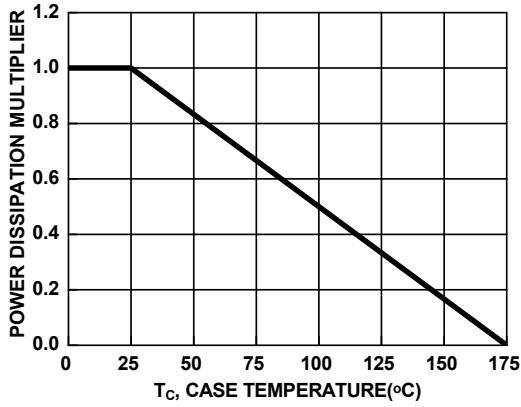


Figure 1. Normalized Power Dissipation vs. Case Temperature

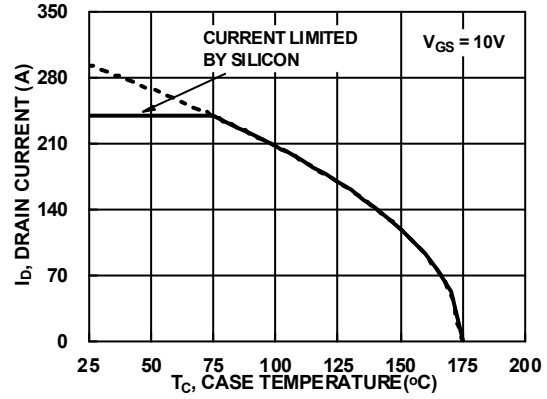


Figure 2. Maximum Continuous Drain Current vs. Case Temperature

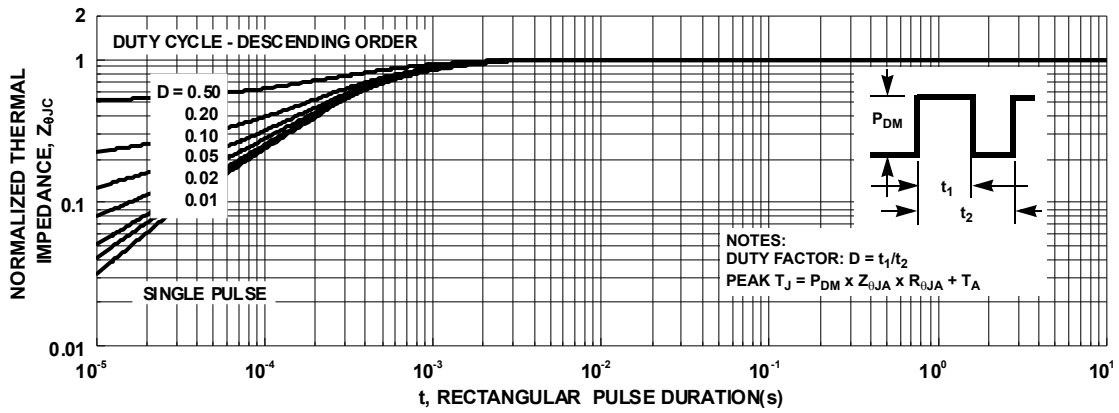


Figure 3. Normalized Maximum Transient Thermal Impedance

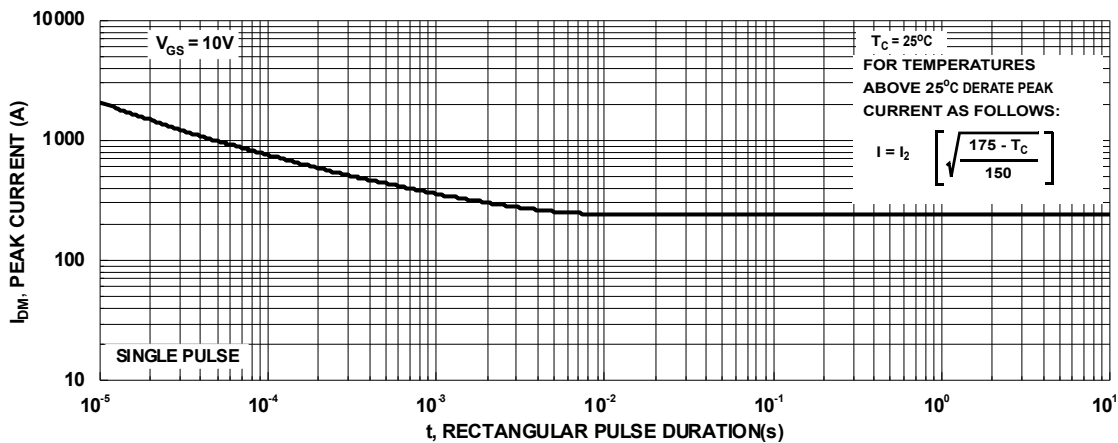


Figure 4. Peak Current Capability

**Typical Characteristics** (The dynamic, switching characteristics and graphs are in reference to the FDBL86363\_F085 (TOLL) datasheet (Low side MOSFET))

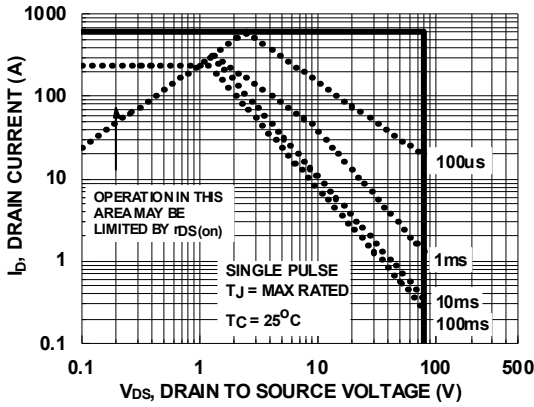


Figure 5. Forward Bias Safe Operating Area

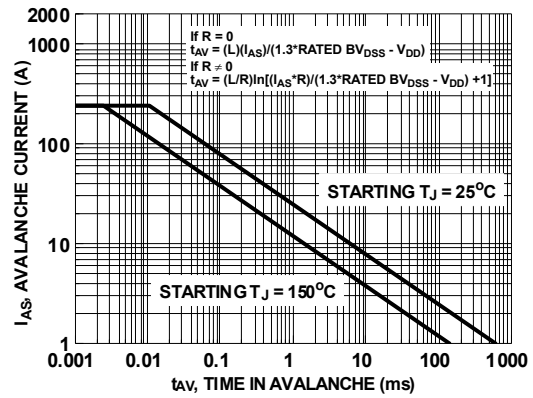


Figure 6. Unclamped Inductive Switching Capability

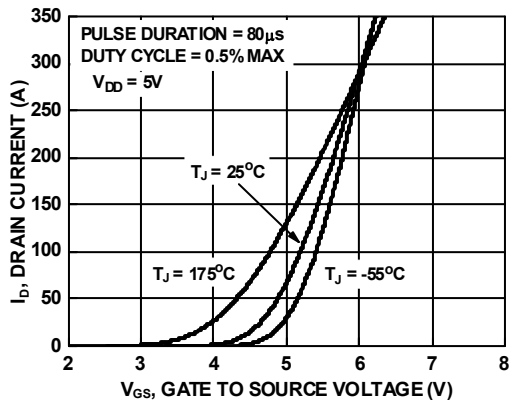


Figure 7. Transfer Characteristics

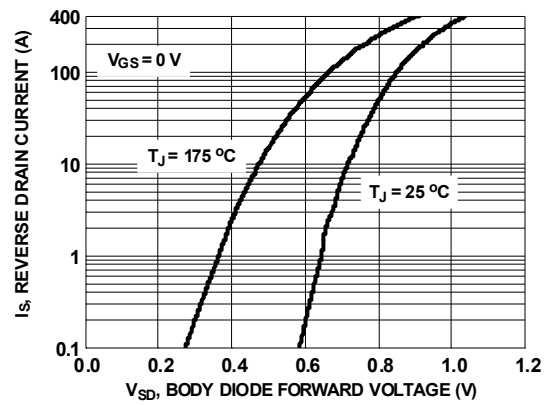


Figure 8. Forward Diode Characteristics

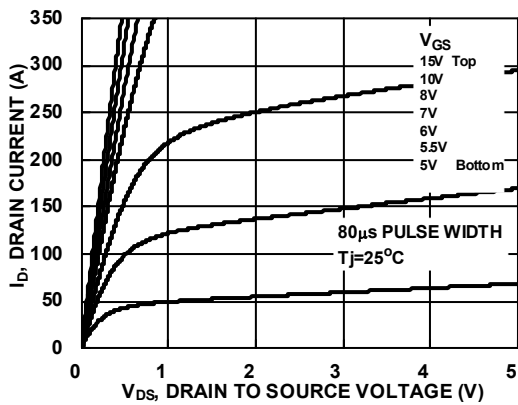


Figure 9. Saturation Characteristics

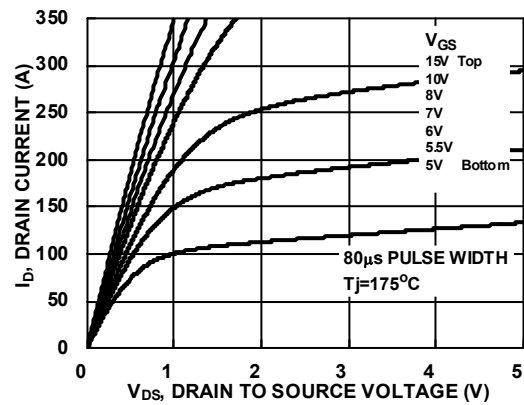


Figure 10. Saturation Characteristics

**Typical Characteristics** (The dynamic, switching characteristics and graphs are in reference to the FDBL86363\_F085 (TOLL) datasheet (Low side MOSFET))

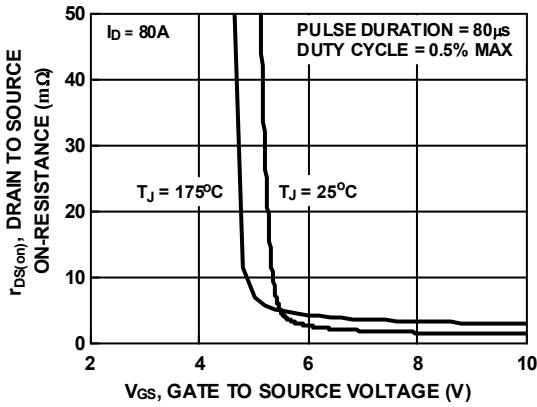


Figure 11.  $R_{DS(on)}$  vs. Gate Voltage

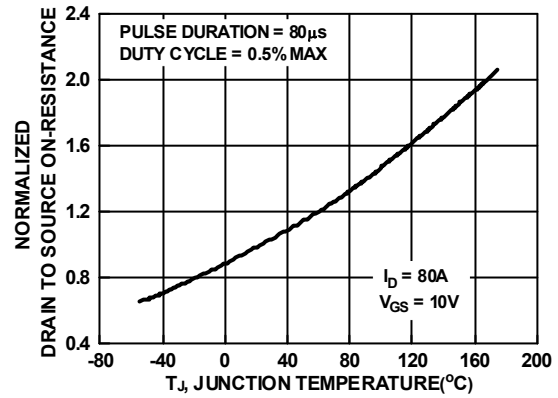


Figure 12. Normalized  $R_{DS(on)}$  vs. Junction Temperature

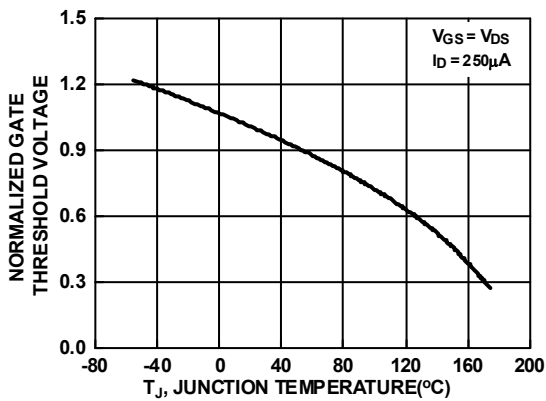


Figure 13. Normalized Gate Threshold Voltage vs. Temperature

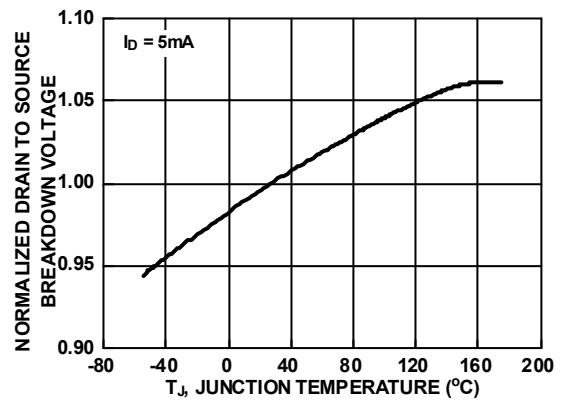


Figure 14. Normalized Drain to Source Breakdown Voltage vs. Junction Temperature

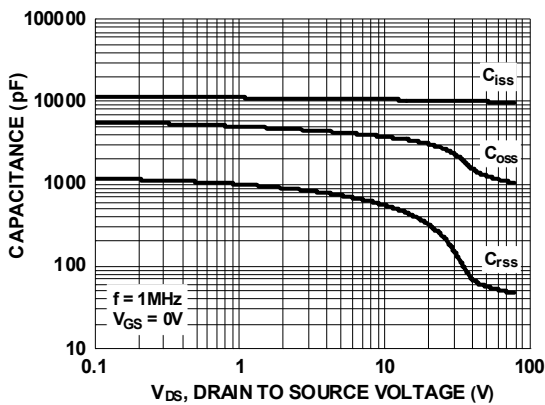


Figure 15. Capacitance vs. Drain to Source Voltage

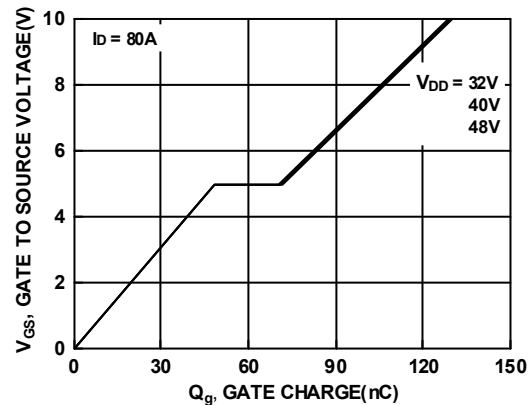
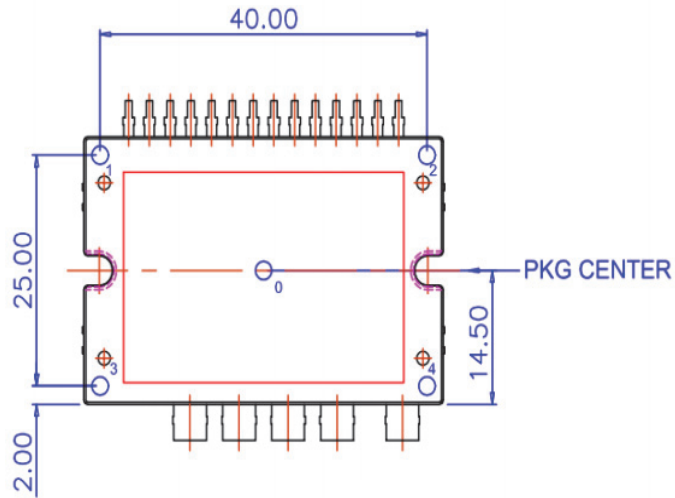


Figure 16. Gate Charge vs. Gate to Source Voltage

### Mechanical Characteristics and Ratings

Parameter	Condition	Limits			Units
		Min.	Typ.	Max.	
Device Flatness	Note Fig.15	0	-	+150	μm
Mounting Torque	Mounting Screw: -M3, Recommended 0.7N.m	0.4	-	0.8	N.m
Weight		-	20	-	g



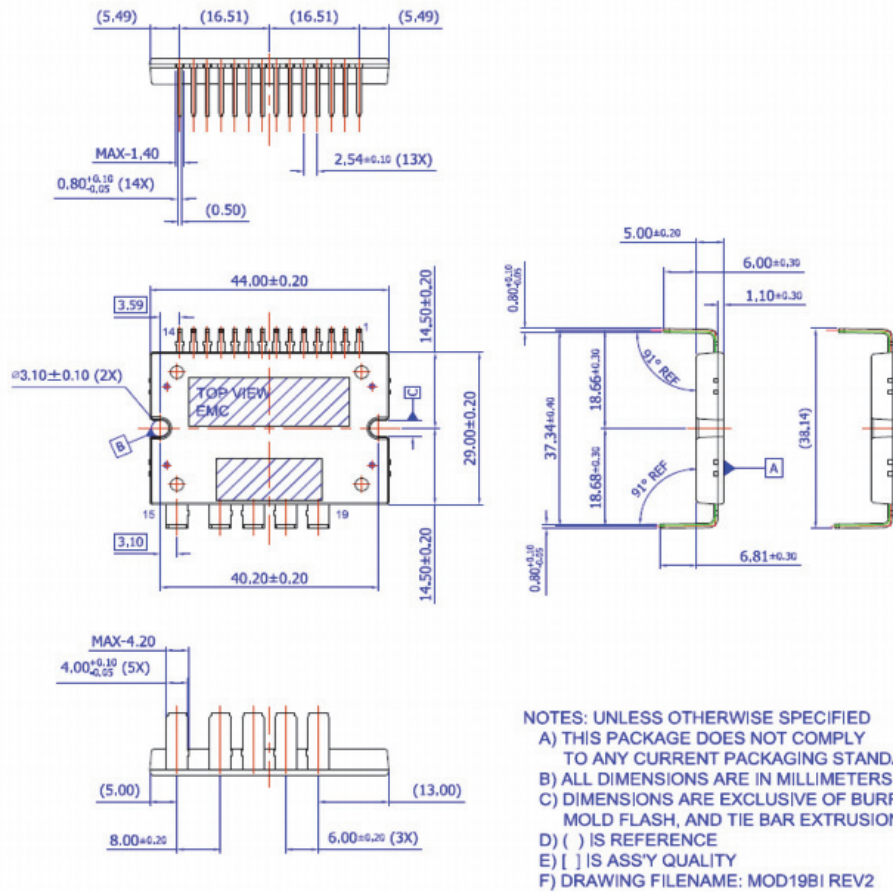
FLATNESS : MAX. 150um

-. MEASURING AT INDICATING POINTS  
1, 2, 3, AND 4 (BASED ON "0")

### Package Marking and Ordering Information

Device Marking	Packing Type	Quantity
FTCO3V85A1	Tube	11

## Detailed Package Outline Drawings



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